

<b>Notice of References Cited</b>	Application/Control No. 10/582,167		Applicant(s)/Patent Under Reexamination KEEN ET AL.	
	Examiner Christle I. Marshall		Art Unit 2887	Page 1 of 1

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*	B	US-2005/0079859 A1	04-2005	Eakin, William Joseph	455/411
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